



Docket No.: H6808.0024/P024
(PATENT)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:
Hiroshi Miyai et al.

Application No.: 10/669,253

Art Unit: N/A

Filed: September 25, 2003

Examiner: Not Yet Assigned

For: AN INSPECTION METHOD AND
APPARATUS USING AN ELECTRON
BEAM (AS AMENDED)

FIRST PRELIMINARY AMENDMENT

MS Non-Fee Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

INTRODUCTORY COMMENTS

Prior to examination on the merits, please amend the above-identified U.S. patent application as follows:

Amendments to the Specification begin on page 2 of this paper.

Remarks begin on page 3 of this paper.